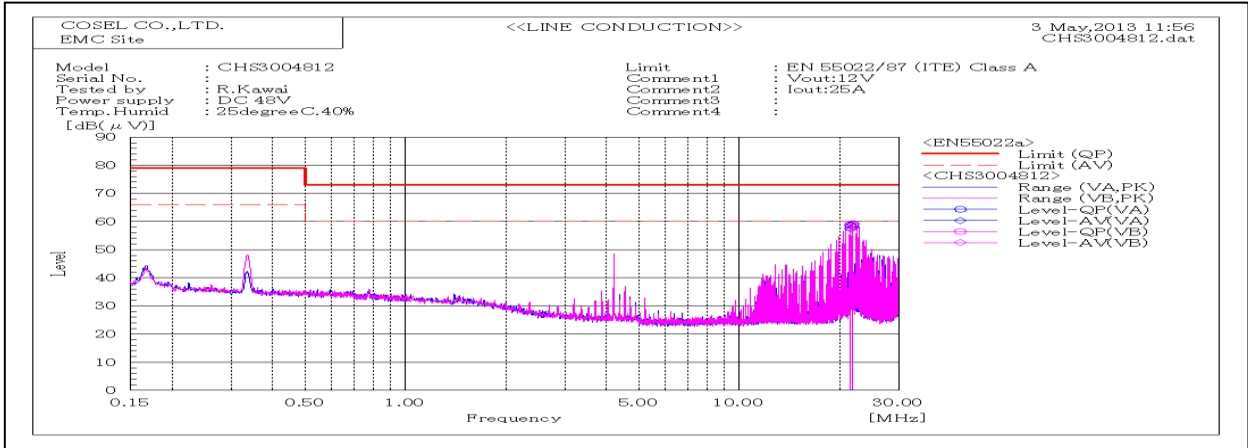
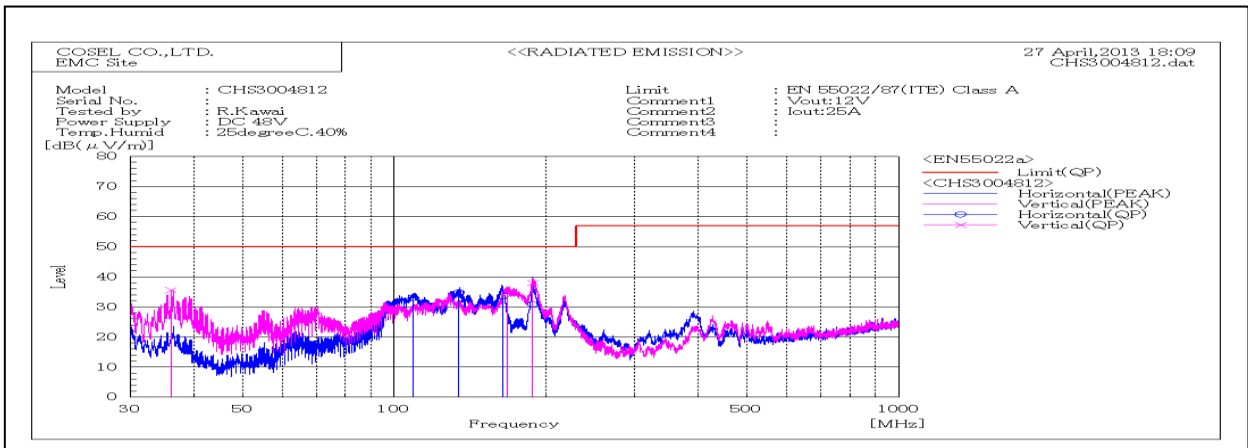


DATA SHEET		Date	10-Jun-13
Model	CHS3004812	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	R.Kawai



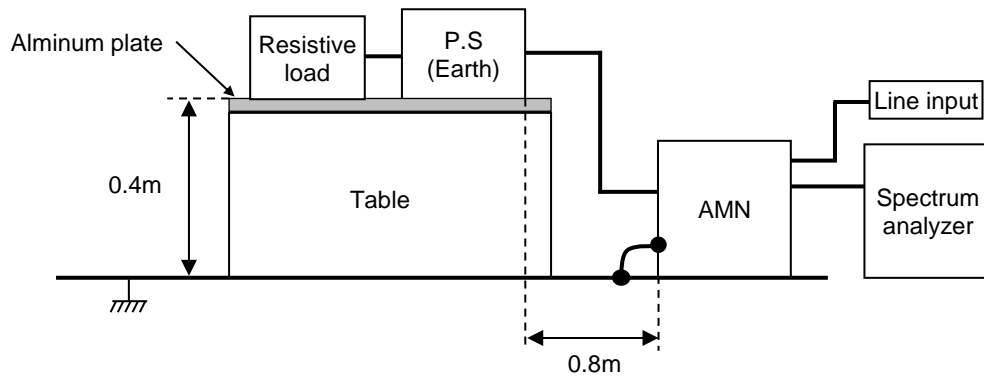
Frequency MHz	Harm	Line Phase	Reading dB(uV)	Factor dB	Level dB(uV)	Limit dB(uV)		Margin dB	Pass/Fail	Remark
			QP		QP	QP	AV			
21.55295		VB	38.2	20.9	59.1	73	60	13.9	Pass	
21.5648		VA	37.6	21	58.6	73	60	14.4	Pass	
21.9		VB	38.3	20.9	59.2	73	60	13.8	Pass	
21.9033		VA	38	21	59	73	60	14	Pass	



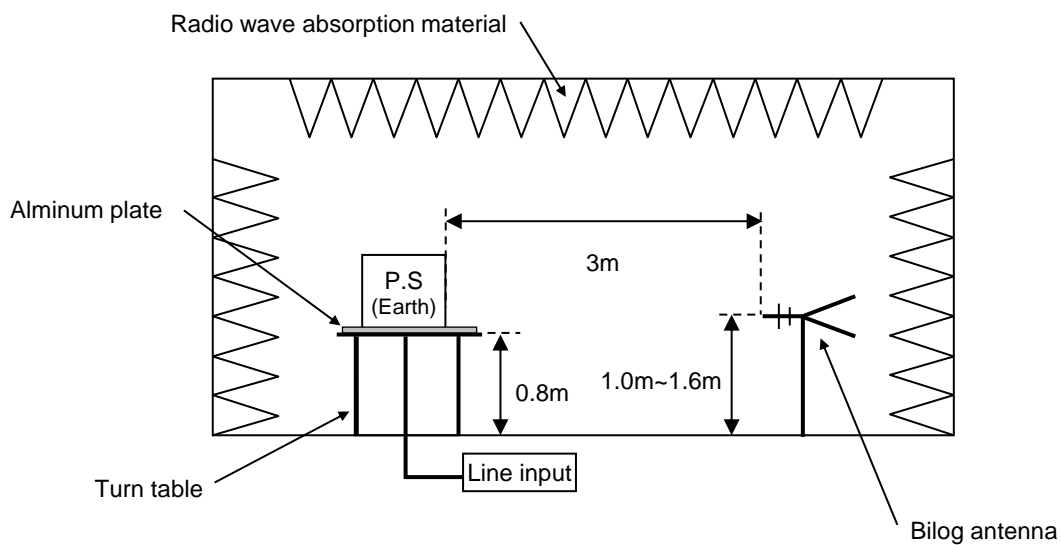
Frequency MHz	Polarization	Stability	Reading dB(uV)	Space Loss dB	Level dB(mW)	Limit dB(mW)	Margin dB	Pass/Fail	Height cm	Angle deg	Remark
			QP		QP	QP					
36.161	V	Stable	50.7	-15.1	35.6	50	14.4	Pass	101	144	
109.124	H	Stable	53.5	-20.5	33	50	17	Pass	157	241	
134.399	H	Stable	54.8	-19.9	34.9	50	15.1	Pass	153	233	
163.996	H	Stable	55.2	-21.6	33.6	50	16.4	Pass	138	2	
167.67	V	Stable	52.1	-17	35.1	50	14.9	Pass	104	344	
188.247	V	Stable	53.7	-15.8	37.9	50	12.1	Pass	156	2	
188.201	H	Stable	53.2	-22.3	30.9	50	19.1	Pass	138	51	

DATA SHEET		Date	10-Jun-13
Model	Circuit used for measurement	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	R.Kawai

1. Line conduction



2. Radiated emission

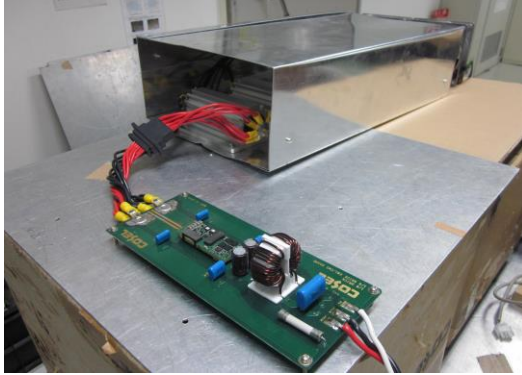


Conditions

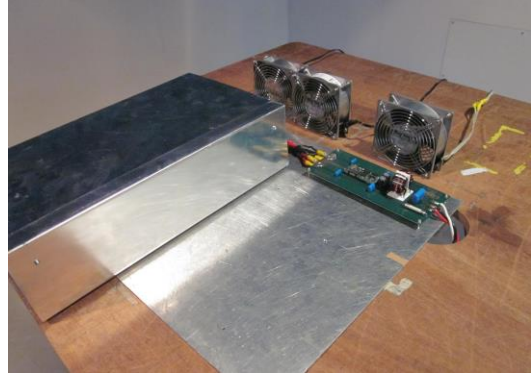
Test : EMI
 Model Name : CHS30048□

○Photographs of Test Set-Up

LINE CONDUCTION



RADIATED EMISSION



○Testing circuitry

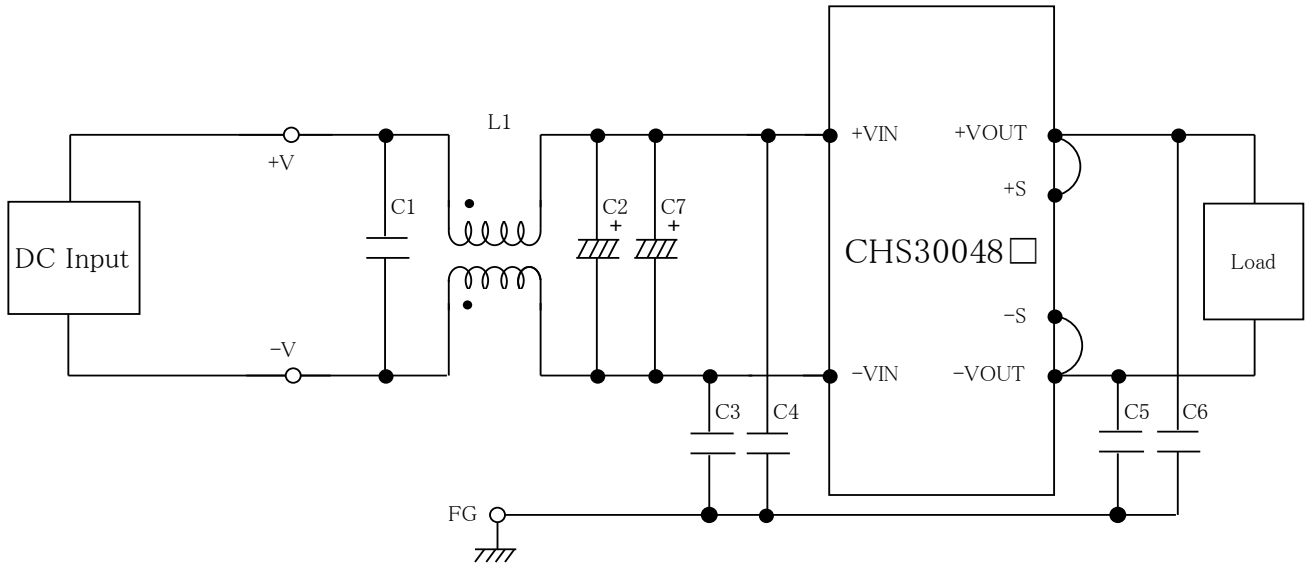


Fig.1 Testing circuitry

- L1 : 1mH SC-15-10J (TOKIN)
- C1 : 250V 2.2 μ F FPD22E225J4 (NITSUKO)
- C2,C7 : 100V 100 μ F PWseries (nichicon)
- C3,C4 : 630V 0.068 μ F FPD22J683J4 (NITSUKO)
- C5,C6 : 630V 0.033 μ F FPD22J333J4 (NITSUKO)